

# FDB12N50U

## N-Channel MOSFET, FRFET

### 500V, 10A, 0.8Ω

#### Features

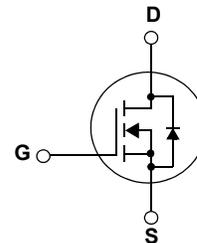
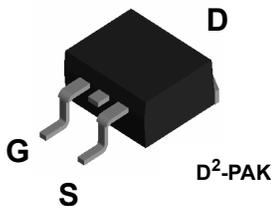
- $R_{DS(on)} = 0.65\Omega$  (Typ.) @  $V_{GS} = 10V, I_D = 5A$
- Low gate charge (Typ. 21nC)
- Low  $C_{rss}$  (Typ. 11pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- RoHS compliant



#### Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advance technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switching mode power supplies and active power factor correction.



#### MOSFET Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted\*

Symbol	Parameter	Ratings	Units
$V_{DSS}$	Drain to Source Voltage	500	V
$V_{GSS}$	Gate to Source Voltage	$\pm 30$	V
$I_D$	Drain Current	-Continuous ( $T_C = 25^\circ\text{C}$ )	10
		-Continuous ( $T_C = 100^\circ\text{C}$ )	6
$I_{DM}$	Drain Current	- Pulsed (Note 1)	40
$E_{AS}$	Single Pulsed Avalanche Energy	(Note 2)	456
$I_{AR}$	Avalanche Current	(Note 1)	10
$E_{AR}$	Repetitive Avalanche Energy	(Note 1)	16.5
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	20
$P_D$	Power Dissipation	( $T_C = 25^\circ\text{C}$ )	165
		- Derate above $25^\circ\text{C}$	1.33
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$
$T_L$	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds	300	$^\circ\text{C}$

\*Drain current limited by maximum junction temperature

#### Thermal Characteristics

Symbol	Parameter	Ratings	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.75	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	

**Package Marking and Ordering Information**  $T_C = 25^\circ\text{C}$  unless otherwise noted

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDB12N50U	FDB12N50UTM_WS	D2-PAK	330mm	24mm	800

**Electrical Characteristics**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
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**Off Characteristics**

$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 250\mu\text{A}, V_{GS} = 0\text{V}, T_J = 25^\circ\text{C}$	500	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$ , Referenced to $25^\circ\text{C}$	-	0.7	-	$V/^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 500\text{V}, V_{GS} = 0\text{V}$ $V_{DS} = 400\text{V}, T_C = 125^\circ\text{C}$	-	-	25 250	$\mu\text{A}$
$I_{GSS}$	Gate to Body Leakage Current	$V_{GS} = \pm 30\text{V}, V_{DS} = 0\text{V}$	-	-	$\pm 100$	nA

**On Characteristics**

$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250\mu\text{A}$	3.0	-	5.0	V
$R_{DS(on)}$	Static Drain to Source On Resistance	$V_{GS} = 10\text{V}, I_D = 5\text{A}$	-	0.65	0.8	$\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS} = 40\text{V}, I_D = 5\text{A}$ (Note 4)	-	11	-	S

**Dynamic Characteristics**

$C_{iss}$	Input Capacitance	$V_{DS} = 25\text{V}, V_{GS} = 0\text{V}$ $f = 1\text{MHz}$	-	1050	1395	pF
$C_{oss}$	Output Capacitance		-	140	190	pF
$C_{rss}$	Reverse Transfer Capacitance		-	11	17	pF
$Q_{g(tot)}$	Total Gate Charge at 10V	$V_{DS} = 400\text{V}, I_D = 10\text{A}$ $V_{GS} = 10\text{V}$ (Note 4, 5)	-	21	30	nC
$Q_{gs}$	Gate to Source Gate Charge		-	6	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge		-	9	-	nC

**Switching Characteristics**

$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 250\text{V}, I_D = 10\text{A}$ $R_G = 25\Omega$ (Note 4, 5)	-	35	80	ns
$t_r$	Turn-On Rise Time		-	45	100	ns
$t_{d(off)}$	Turn-Off Delay Time		-	60	130	ns
$t_f$	Turn-Off Fall Time		-	35	80	ns

**Drain-Source Diode Characteristics**

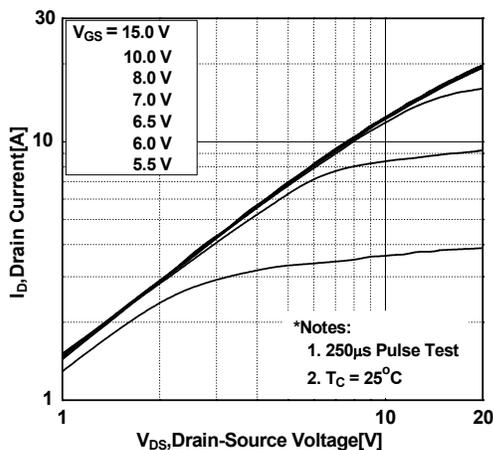
$I_S$	Maximum Continuous Drain to Source Diode Forward Current	-	-	10	A	
$I_{SM}$	Maximum Pulsed Drain to Source Diode Forward Current	-	-	40	A	
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS} = 0\text{V}, I_{SD} = 12\text{A}$	-	-	1.6	V
$t_{rr}$	Reverse Recovery Time	$V_{GS} = 0\text{V}, I_{SD} = 12\text{A}$	-	60	-	ns
$Q_{rr}$	Reverse Recovery Charge	$di_F/dt = 100\text{A}/\mu\text{s}$ (Note 4)	-	0.1	-	$\mu\text{C}$

**Notes:**

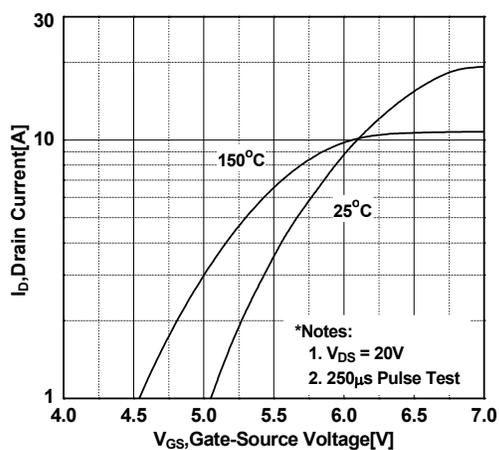
1. Repetitive Rating: Pulse width limited by maximum junction temperature
2.  $L = 9\text{mH}, I_{AS} = 10\text{A}, V_{DD} = 50\text{V}, R_G = 25\Omega$ , Starting  $T_J = 25^\circ\text{C}$
3.  $I_{SD} \leq 10\text{A}, di/dt \leq 200\text{A}/\mu\text{s}, V_{DD} \leq BV_{DSS}$ , Starting  $T_J = 25^\circ\text{C}$
4. Pulse Test: Pulse width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$
5. Essentially Independent of Operating Temperature Typical Characteristics

## Typical Performance Characteristics

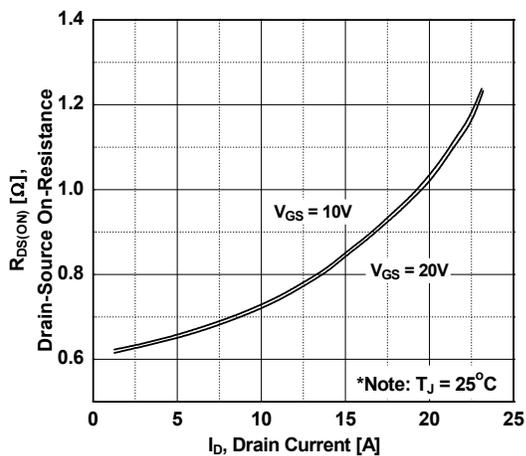
**Figure 1. On-Region Characteristics**



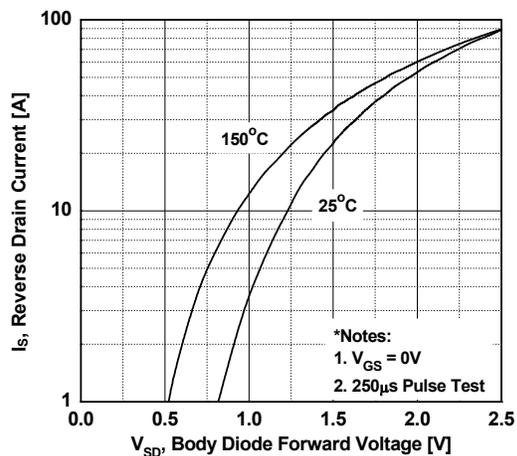
**Figure 2. Transfer Characteristics**



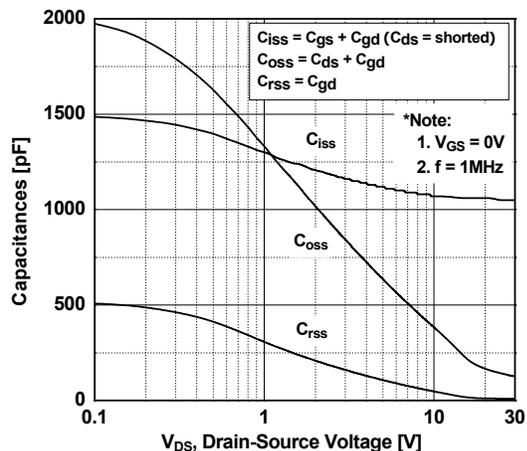
**Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage**



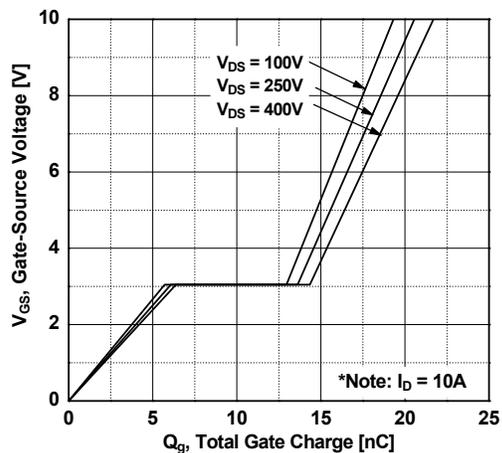
**Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature**



**Figure 5. Capacitance Characteristics**



**Figure 6. Gate Charge Characteristics**



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

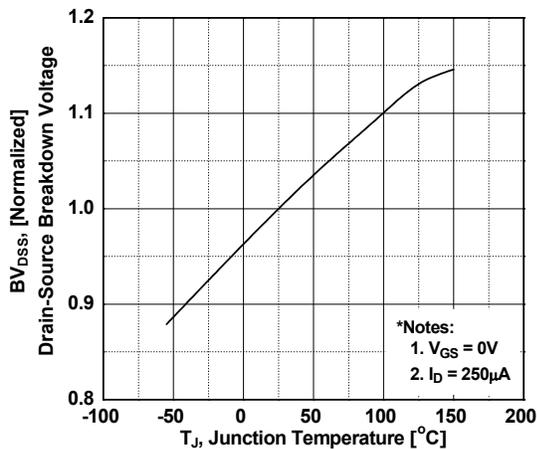


Figure 8. Maximum Safe Operating Area

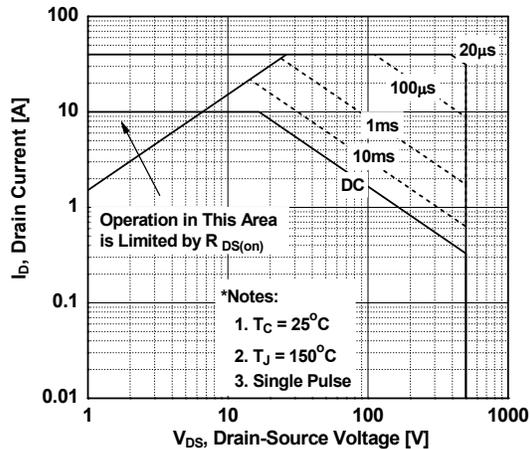


Figure 9. Maximum Drain Current vs. Case Temperature

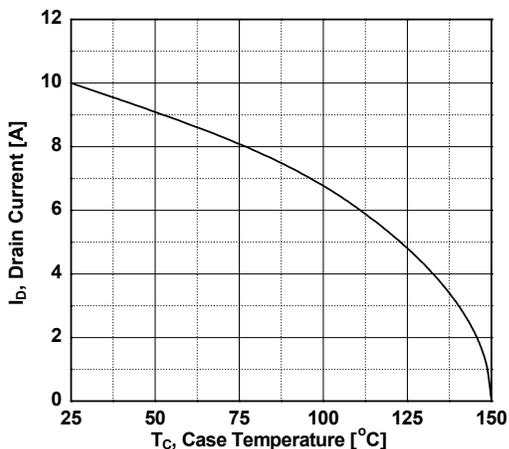
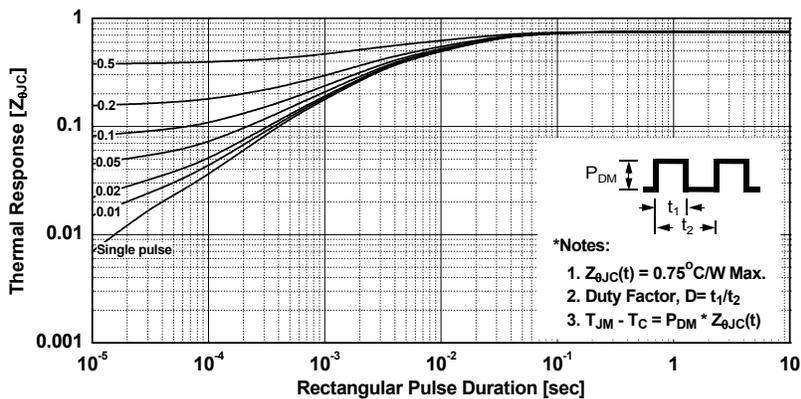
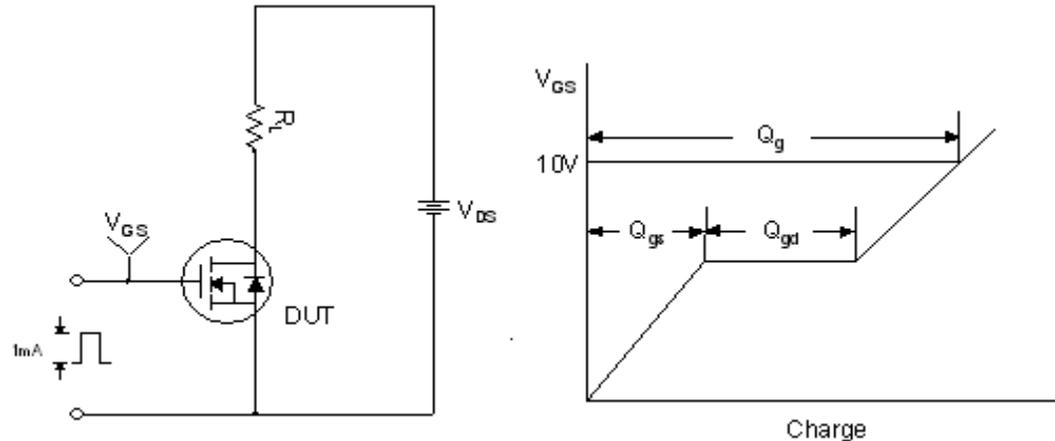


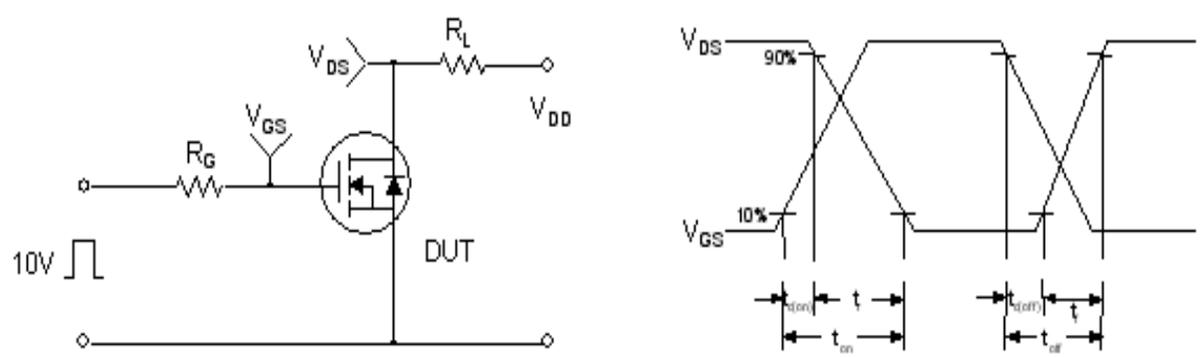
Figure 10. Transient Thermal Response Curve



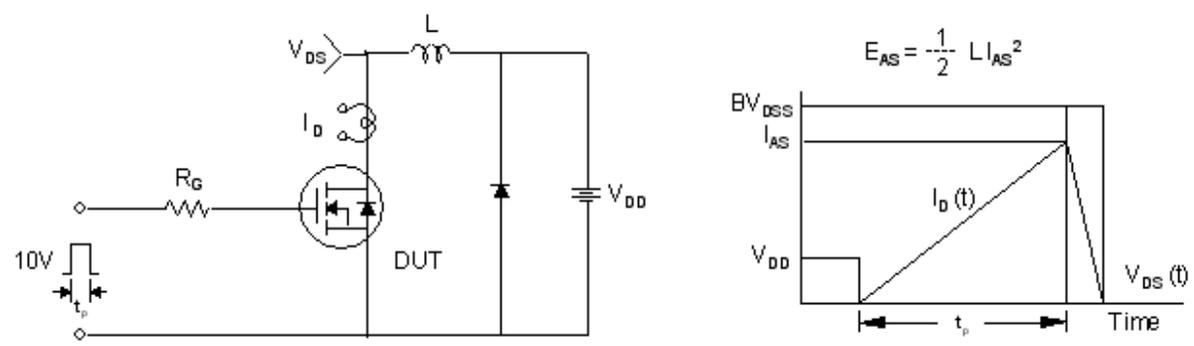
**Gate Charge Test Circuit & Waveform**



**Resistive Switching Test Circuit & Waveforms**

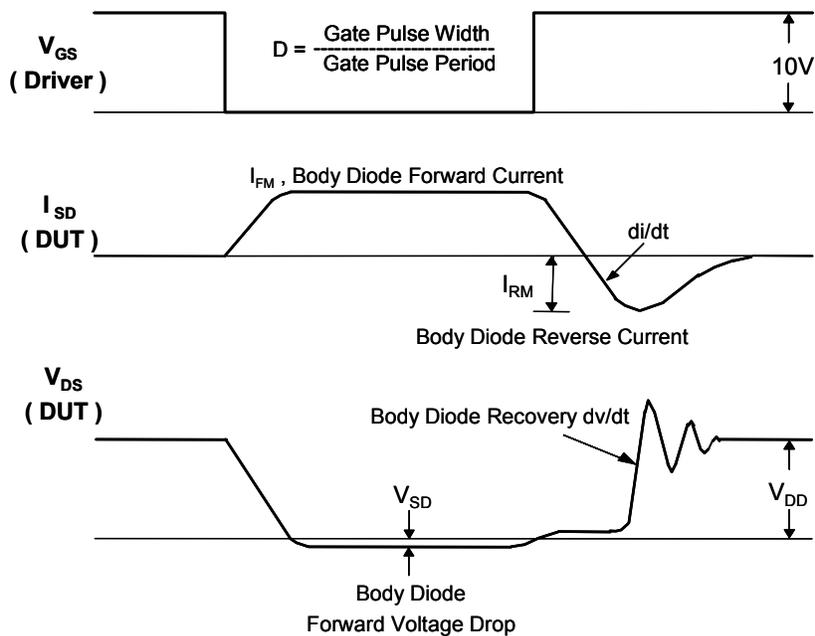
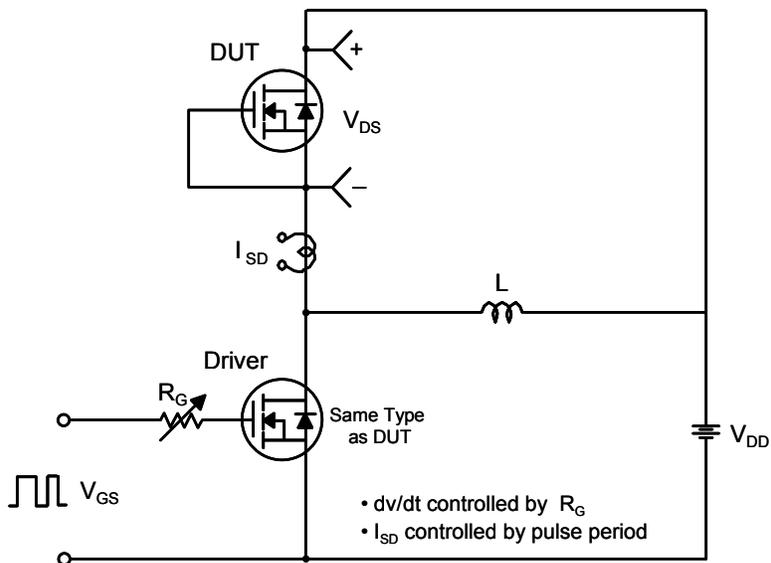


**Unclamped Inductive Switching Test Circuit & Waveforms**



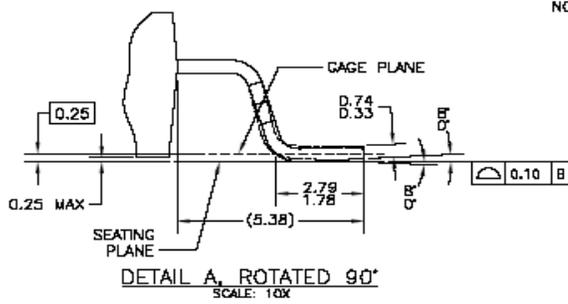
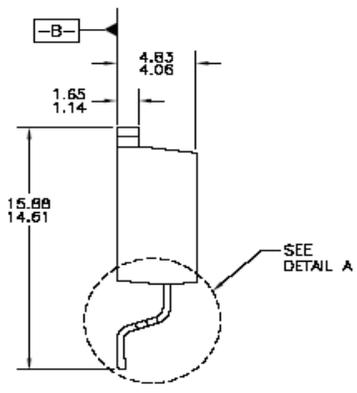
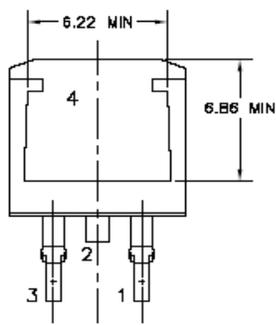
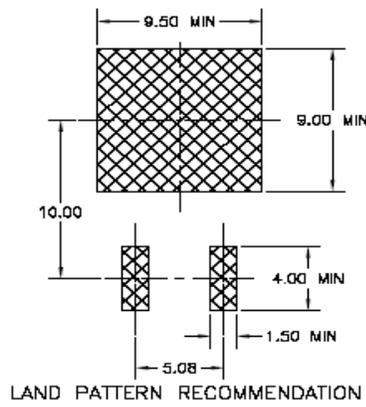
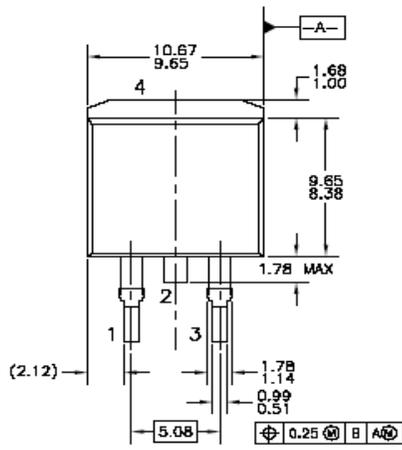
$$E_{AS} = \frac{1}{2} L I_{AS}^2$$

Peak Diode Recovery dv/dt Test Circuit & Waveforms



**Mechanical Dimensions**

**D2-PAK**



- NOTES: UNLESS OTHERWISE SPECIFIED
- A) ALL DIMENSIONS ARE IN MILLIMETERS.
  - B) REFERENCE JEDEC, TO-263, ISSUE D, VARIATION AB, DATED JULY 2003.
  - C) DIMENSIONING AND TOLERANCING PER ANSI Y14.5M - 1982.
  - D) LOCATION OF THE PIN HOLE MAY VARY (LOWER LEFT CORNER, LOWER CENTER AND CENTER OF THE PACKAGE).
  - E) PRESENCE OF TRIMMED CENTER LEAD IS OPTIONAL.

TO283AD2REVD

Dimensions in Millimeters



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| BitSiC®   | Green Bridge™   | QFET®   | TinyBoost™  |
| Build it Now™   | Green FPS™  | QS™   | TinyBuck™   |
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